



# **EMC-OPTIMIZED CAN TRANSCEIVER**

## **FEATURES**

- Qualified for Automotive Applications
- Customer-Specific Configuration Control Can Be Supported Along With Major-Change Approval
- Improved Drop-In Replacement for TJA1050
- Meets or Exceeds the Requirements of ISO 11898-2
- GIFT/ICT Compliant
- ESD Protection up to ±8 kV (Human-Body Model) on Bus Pins
- High Electromagnetic Immunity (EMI)
- Low Electromagnetic Emissions (EME)
- Bus-Fault Protection of –27 V to 40 V
- Dominant Time-Out Function
- Thermal Shutdown Protection
- Power-Up/Down Glitch-Free Bus Inputs and Outputs
  - High Input Impedance With Low V<sub>CC</sub>
  - Monotonic Outputs During Power Cycling

#### APPLICATIONS

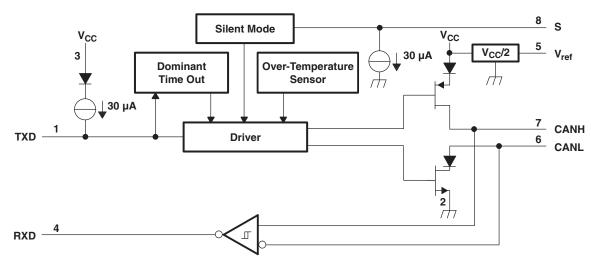
- GMW3122 Dual-Wire CAN Physical Layer
- SAE J2284 High-Speed CAN for Automotive Applications
- SAE J1939 Standard Data Bus Interface
- ISO 11783 Standard Data Bus Interface
- NMEA 2000 Standard Data Bus Interface
- Industrial Automation
  - DeviceNet<sup>™</sup> Data Buses (Vendor ID #806)

### DESCRIPTION

The SN65HVD1050 meets or exceeds the specifications of the ISO 11898 standard for use in applications employing a Controller Area Network (CAN). The device is qualified for use in automotive applications.

As a CAN transceiver, this device provides differential transmit capability to the bus and differential receive capability to a CAN controller at signaling rates up to 1 megabit per second (Mbps)<sup>(1)</sup>.

 The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).



### FUNCTION BLOCK DIAGRAM

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet. DeviceNet is a trademark of Texas Instruments.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

# **DESCRIPTION (CONTINUED)**

Designed for operation is especially harsh environments, the SN65HVD1050 features cross-wire, over-voltage, and loss of ground protection from –27 V to 40 V, over-temperature protection, a –12-V to 12-V common-mode range, and withstands voltage transients from –200 V to 200 V according to ISO 7637.

Pin 8 provides for two different modes of operation: high-speed or silent mode. The high-speed mode of operation is selected by connecting S (pin 8) to ground.

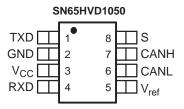
If a high logic level is applied to the S pin of the SN65HVD1050, the device enters a listen-only silent mode during which the driver is switched off while the receiver remains fully functional.

In silent mode, all bus activity is passed by the receiver output to the local protocol controller. When data transmission is required, the local protocol controller reverses this low-current silent mode by placing a logic low on the S pin to resume full operation.

A dominant time-out circuit in the SN65HVD1050 prevents the driver from blocking network communication with a hardware or software failure. The time-out circuit is triggered by a falling edge on TXD (pin 1). If no rising edge is seen before the time-out constant of the circuit expires, the driver is disabled. The circuit is then reset by the next rising edge on TXD.

 $V_{ref}$  (pin 5) is available as a  $V_{CC}/2$  voltage reference.

The SN65HVD1050 is characterized for operation from –40°C to 125°C.



#### ORDERING INFORMATION<sup>(1)</sup>

PART NUMBER	PACKAGE <sup>(2)</sup>	MARKED AS	ORDERING NUMBER
SN65HVD1050-Q1	D1050-Q1 SOIC-8 H1050Q SN65HVD1050QDRQ1 (r		SN65HVD1050QDRQ1 (reel)

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

#### Application Hint: CAN Nodes Using Common-Mode Chokes

The SN65HVD1050 has been EMC optimized to allow use in CAN systems without a common-mode choke. However, sometimes the CAN network and termination architecture may require their use. If a common-mode choke is used in a CAN node where bus-line shorts to dc voltages may be possible, care should be taken in the choice of common-mode choke (winding type, core type, and value) along with the termination and protection scheme of the node and bus. During CAN bus shorts to dc voltages the inductance of the common-mode choke may cause inductive flyback transients. Some combinations of common-mode chokes, bus termination, and shorting voltages take the bus voltages outside the absolute maximum ratings of the device, possibly leading to damage.

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## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

		UNIT
V <sub>CC</sub>	Supply voltage range <sup>(2)</sup>	–0.3 V to 7 V
	Voltage range at any bus terminal (CANH, CANL, V <sub>ref</sub> )	–27 V to 40 V
I <sub>O</sub>	Receiver output current	20 mA
VI	Voltage input range, ac transient pulse <sup>(3)</sup> (CANH, CANL)	–200 V to 200 V
VI	Voltage input range (TXD, S)	–0.5 V to 6 V
TJ	Junction temperature range	-40°C to 170°C
T <sub>A</sub>	Operating free-air temperature range	-40°C to 125°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

(3) Tested in accordance with ISO 7637-1, test pulses 1, 2, 3a, 3b, 5, 6, and 7. ISO 7637-1 transient tests are ac only; if dc may be coupled in with ac transients, externally protect the bus pins within the absolute maximum voltage range at any bus terminal (–27 V to 40 V). If common-mode chokes are used in the system and the bus lines may be shorted to dc, ensure that the choke type and value in combination with the node termination and shorting voltage either will not create inductive flyback outside of voltage maximum specification or use an external transient-suppression circuit to protect the transceiver from the inductive transients

## **ELECTROSTATIC DISCHARGE PROTECTION**

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	
	Human Rady Madal <sup>(2)</sup>	Bus terminals and GND	±8 kV
Electrostatic discharge (1)	Human-Body Model <sup>(2)</sup>	All pins	±4 kV
	Charged-Device Model <sup>(3)</sup>	All pins	±1.5 kV
	Machine Model		±200 V

(1) All typical values at 25°C.

(2) Tested in accordance JEDEC Standard 22, Test Method A114-A.

(3) Tested in accordance JEDEC Standard 22, Test Method C101.

### **RECOMMENDED OPERATING CONDITIONS**

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		4.75	5.25	V
$V_{\text{I}} \text{ or } V_{\text{IC}}$	Voltage at any bus terminal (separately or common mode)		-12	12	V
V <sub>IH</sub>	High-level input voltage	TXD, S	2	5.25	V
V <sub>IL</sub>	Low-level input voltage	TXD, S	0	0.8	V
V <sub>ID</sub>	Differential input voltage		-6	6	V
1	Lich lovel output outpot	Driver	-70		~ ^
I <sub>OH</sub>	High-level output current	Receiver	-2		mA
1		Driver		70	~ ^
I <sub>OL</sub> Low-level output	Low-level output current	Receiver		2	mA
TJ	Junction temperature	See Thermal Characteristics table		150	°C

#### SUPPLY CURRENT

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		Silent mode	S at $V_{CC}$ , $V_I = V_{CC}$		6	10	
I <sub>CC</sub>	5-V supply current	Dominant	$V_{I}$ = 0 V, 60- $\Omega$ load, S at 0 V		50	70	mA
	Recessive	Recessive	$V_I = V_{CC}$ , No load, S at 0 V		6	10	



# **DEVICE SWITCHING CHARACTERISTICS**

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
t <sub>d(LOOP1)</sub>	Total loop delay, driver input to receiver output, recessive to dominant	S at 0 V, See Figure 9	90	230	ns
t <sub>d(LOOP2)</sub>	Total loop delay, driver input to receiver output, dominant to recessive	S at 0 V, See Figure 9	90	230	ns

# DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
M	Due output veltage (deminant)	CANH	$V_{I} = 0 V$ , S at 0 V, $R_{I} = 60 \Omega$ , See Figure 1	2.9	3.4	4.5	V
V <sub>O(D)</sub>	Bus output voltage (dominant)	CANL	and Figure 2			1.5	V
V <sub>O(R)</sub>	Bus output voltage (recessive)		$V_{I}$ = 3 V, S at 0 V, $R_{L}$ = 60 $\Omega,$ See Figure 1 and Figure 2	2	2.3	3	V
M	Differential output valtage (dom	inant)	$V_I = 0 V, R_L = 60 \Omega, S at 0 V, See Figure 1, Figure 2, and Figure 3$	1.5		3	V
V <sub>OD(D)</sub>	Differential output voltage (dominant)		$V_I = 0 V$ , $R_L = 45 \Omega$ , S at 0 V, See Figure 1, Figure 2, and Figure 3	1.4		3	V
M	Differential output voltage (recessive)		$V_I = 3 V$ , S at 0 V, See Figure 1 and Figure 2	-0.012		0.012	V
V <sub>OD(R)</sub>	Differential output voltage (rece	55IVE)	$V_I = 3 V, S at 0 V, No Load$	-0.5	-0.5		v
V <sub>OC(ss)</sub>	Steady state common-mode output voltage		S at 0 V, Figure 8	2	2.3	3	V
$\Delta V_{OC(ss)}$	Change in steady-state commo output voltage	n-mode			30		mV
I <sub>IH</sub>	High-level input current, TXD in	put	V <sub>I</sub> at V <sub>CC</sub>	-2		2	
IIL	Low-level input current, TXD in	out	V <sub>I</sub> at 0 V	-50		-10	μΑ
I <sub>O(off)</sub>	Power-off TXD output current		V <sub>CC</sub> at 0 V, TXD at 5 V			1	
			V <sub>CANH</sub> = -12 V, CANL open, See Figure 11	-105	-72		
1	Chart circuit standy state output	+	V <sub>CANH</sub> = 12 V, CANL open, See Figure 11		0.36	1	A
I <sub>OS(ss)</sub>	Short-circuit steady-state outpu	current	$V_{CANL} = -12 V$ , CANH open, See Figure 11	-1	-0.5		mA
			V <sub>CANL</sub> = 12 V, CANH open, See Figure 11		71	105	1
Co	Output capacitance		See receiver input capacitance				

(1) All typical values are at  $25^{\circ}$ C with a 5-V supply.

# DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high level output	S at 0 V, See Figure 4	25	65	120	ns
t <sub>PHL</sub>	Propagation delay time, high-to-low level output	S at 0 V, See Figure 4	25	45	120	ns
t <sub>r</sub>	Differential output signal rise time	S at 0 V, See Figure 4		25		ns
t <sub>f</sub>	Differential output signal fall time	S at 0 V, See Figure 4		50		ns
t <sub>en</sub>	Enable time from silent mode to dominant	See Figure 7			1	μs
t <sub>(dom)</sub>	Dominant time out	↓V <sub>I</sub> , See Figure 10	300	450	700	μs



## **RECEIVER ELECTRICAL CHARACTERISTICS**

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
V <sub>IT+</sub>	Positive-going input threshold voltage	S at 0 V, See Table 1		800	900	mV
V <sub>IT-</sub>	Negative-going input threshold voltage	S at 0 V, See Table 1	500	650		mV
V <sub>hys</sub>	Hysteresis voltage (V <sub>IT+</sub> – V <sub>IT–</sub> )		100	125		mV
V <sub>OH</sub>	High-level output voltage	$I_0 = -2$ mA, See Figure 6	4	4.6		V
V <sub>OL</sub>	Low-level output voltage	I <sub>O</sub> = 2 mA, See Figure 6		0.2	0.4	V
I <sub>I(off)</sub>	Power-off bus input current	CANH or CANL = 5 V, Other pin at 0 V, $V_{CC}$ at 0 V, TXD at 0 V		165	250	μA
I <sub>O(off)</sub>	Power-off RXD leakage current	V <sub>CC</sub> at 0 V, RXD at 5 V			20	μA
CI	Input capacitance to ground (CANH or CANL)	TXD at 3 V, V <sub>I</sub> = 0.4 sin (4E6πt) + 2.5 V		13		pF
CID	Differential input capacitance	TXD at 3 V, $V_1 = 0.4 \sin (4E6\pi t)$		5		pF
R <sub>ID</sub>	Differential input resistance	TXD at 3 V, S at 0 V	30		80	kΩ
R <sub>IN</sub>	Input resistance (CANH or CANL)	TXD at 3 V, S at 0 V	15	30	40	kΩ
R <sub>I(m)</sub>	Input resistance matching $[1 - (R_{IN (CANH)} / R_{IN (CANL)})] \times 100\%$	$V_{(CANH)} = V_{(CANL)}$	-3	0	3	%

(1) All typical values are at 25°C with a 5-V supply.

## **RECEIVER SWITCHING CHARACTERISTICS**

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output		60	100	130	ns
t <sub>PHL</sub>	Propagation delay time, high-to-low-level output	S at 0 V or V <sub>CC</sub> , See Figure 6	45	70	130	ns
t <sub>r</sub>	Output signal rise time	S at 0 v or v <sub>CC</sub> , See Figure 6		8		ns
t <sub>f</sub>	Output signal fall time			8		ns

## **S PIN CHARACTERISTICS**

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I <sub>IH</sub>	High level input current	S at 2 V	20	40	70	μA
$I_{IL}$	Low level input current	S at 0.8 V	5	20	30	μA

### **VREF PIN CHARACTERISTICS**

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
$V_{O}$	Reference output voltage	–50 μA < I <sub>O</sub> < 50 μA	$0.4 V_{CC}$	$0.5 V_{CC}$	$0.6 V_{CC}$	V



#### THERMAL CHARACTERISTICS

over recommended operating conditions including operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$\theta_{JA}$	Junction-to-air thermal resistance	Low-K thermal resistance <sup>(1)</sup>	211			0000
		High-K thermal resistance	131			°C/W
$\theta_{JB}$	Junction-to-board thermal resistance			53		°C/W
$\theta_{\text{JC}}$	Junction-to-case thermal resistance			79		°C/W
P <sub>D</sub>	Average power dissipation	$V_{CC}$ = 5 V, $T_J$ = 27°C, $R_L$ = 60 $\Omega,$ S at 0 V, Input to TXD at 500 kHz, 50% duty cycle square wave, CL at RXD = 15 pF	112			
		$V_{CC}$ = 5.5 V, $T_J$ = 130°C, $R_L$ = 45 $\Omega,$ S at 0 V, Input to TXD at 500 kHz, 50% duty cycle square wave, CL at RXD = 15 pF			170	mW
	Thermal shutdown temperature			190		°C

(1) Tested in accordance with the low-K or high-K thermal metric definitions of EIA/JESD51-3 for leaded surface-mount packages.

#### **FUNCTION TABLES**

#### DRIVER<sup>(1)</sup>

INP	UTS	OUTP	BUS STATE	
TXD	S	CANH	CANL	DUS STATE
L	L or Open	Н	L	Dominant
Н	Х	Z	Z	Recessive
Open	Х	Z	Z	Recessive
Х	Н	Z	Z	Recessive

(1) H = high level, L = low level, X = irrelevant, ? = indeterminate, Z = high impedance

#### **RECEIVER**<sup>(1)</sup>

DIFFERENTIAL INPUTS V <sub>ID</sub> = V(CANH) – V(CANL)	OUTPUT RXD	BUS STATE
$V_{ID} \ge 0.9 V$	L	Dominant
$0.5 \text{ V} < \text{V}_{\text{ID}} < 0.9 \text{ V}$	?	?
V <sub>ID</sub> ≤ 0.5 V	Н	Recessive
Open	Н	Recessive

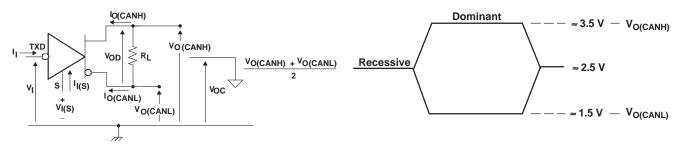
(1) H = high level, L = low level, X = irrelevant, ? = indeterminate, Z = high impedance

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## PARAMETER MEASUREMENT INFORMATION



#### Figure 1. Driver Voltage, Current, and Test Definition



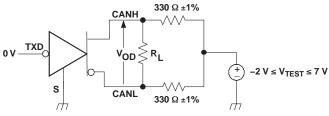


Figure 3. Driver  $V_{OD}$  Test Circuit

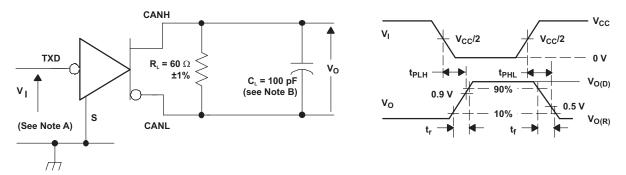


Figure 4. Driver Test Circuit and Voltage Waveforms

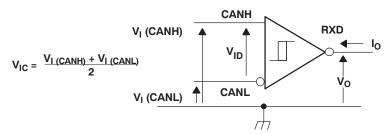
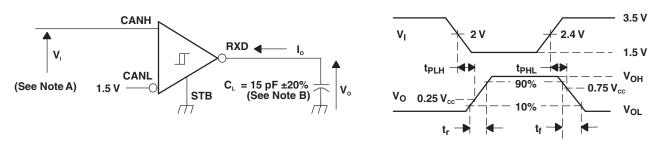


Figure 5. Receiver Voltage and Current Definitions

## PARAMETER MEASUREMENT INFORMATION (continued)

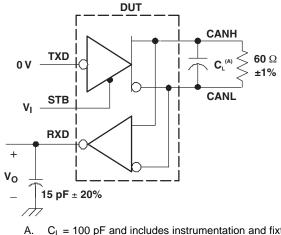


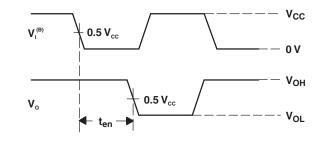
- The input pulse is supplied by a generator having the following characteristics: PRR ≤ 125 kHz, 50% duty cycle, Α.  $t_r \le 6 \text{ ns}, t_f \le 6 \text{ ns}, Z_O = 50 \Omega.$
- $C_L$  includes instrumentation and fixture capacitance within ±20%. В.

#### Figure 6. Receiver Test Circuit and Voltage Waveforms

	OUTPUT					
V <sub>CANH</sub>	V <sub>CANL</sub>	V <sub>ID</sub>		R		
–11.1 V	–12 V	900 mV	L			
12 V	11.1 V	900 mV	L	.,		
–6 V	–12 V	6 V	L	V <sub>OL</sub>		
12 V	6 V	6 V	L			
–11.5 V	–12 V	500 mV	н			
12 V	11.5 V	500 mV	Н	T		
–12 V	-6 V	6 V	Н	V <sub>OH</sub>		
6 V	12 V	6 V	Н	†		
Open	Open	Х	Н	Ţ		

#### **Table 1. Differential Input Voltage Threshold Test**

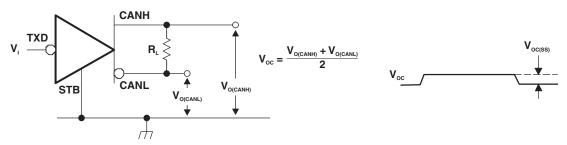




- $C_L$  = 100 pF and includes instrumentation and fixture capacitance within ±20%.
- All V<sub>I</sub> input pulses are supplied by a generator having the following characteristics:  $t_r$  or  $t_f \le 6$  ns, В. pulse repetition rate (PRR) = 125 kHz, 50% duty cycle.

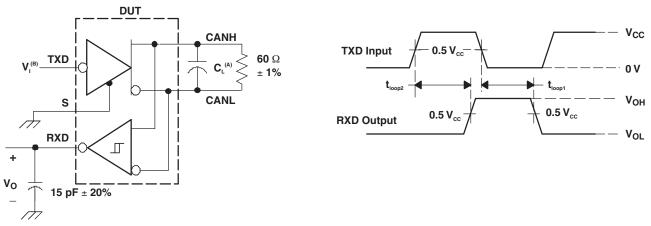
#### Figure 7. ten Test Circuit and Waveforms

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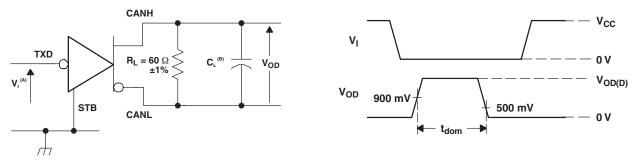
NOTE: All V<sub>I</sub> input pulses are from 0 V to V<sub>CC</sub> and supplied by a generator having the following characteristics:  $t_r$  or  $t_f \le 6$  ns, pulse repetition rate (PRR) = 125 kHz, 50% duty cycle.

#### Figure 8. Common-Mode Output Voltage Test and Waveforms



- A.  $C_L = 100 \text{ pF}$  and includes instrumentation and fixture capacitance within ±20%.
- B. All V<sub>1</sub> input pulses are from 0 V to V<sub>CC</sub> and supplied by a generator having the following characteristics:  $t_r$  or  $t_f \le 6$  ns, pulse repetition rate (PRR) = 125 kHz, 50% duty cycle.

#### Figure 9. t<sub>(LOOP)</sub> Test Circuit and Waveforms



- A. All V<sub>I</sub> input pulses are from 0 V to V<sub>CC</sub> and supplied by a generator having the following characteristics:  $t_r$  or  $t_f \le 6$  ns, pulse repetition rate (PRR) = 500 Hz, 50% duty cycle.
- B.  $C_L = 100 \text{ pF}$  includes instrumentation and fixture capacitance within ±20%.

#### Figure 10. Dominant Time-Out Test Circuit and Waveforms

# SN65HVD1050-Q1



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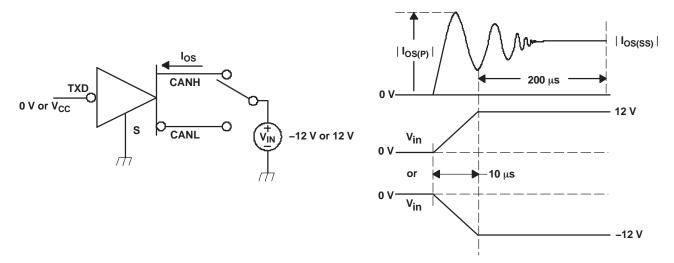
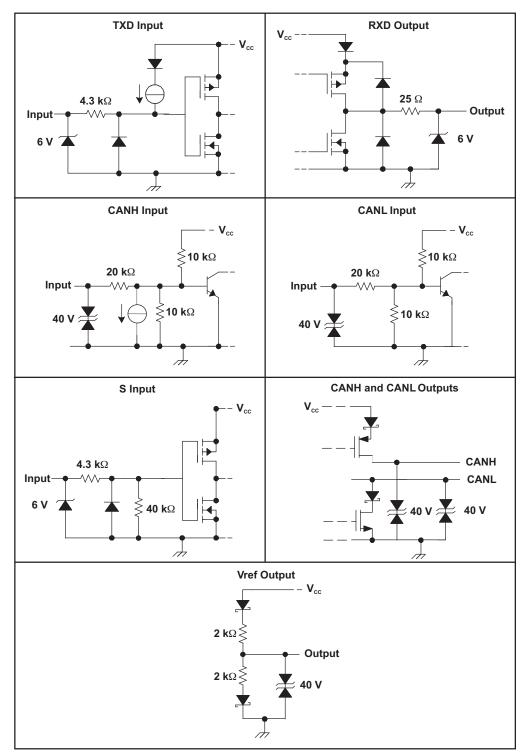


Figure 11. Driver Short-Circuit Current Test and Waveforms



# Equivalent Input and Output Schematic Diagrams





#### PACKAGING INFORMATION

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins I	Package Qty	Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
SN65HVD1050QDRQ1	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

**Important Information and Disclaimer:**The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN65HVD1050-Q1 :

Catalog: SN65HVD1050

Enhanced Product: SN65HVD1050-EP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications

D (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.

Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.

E. Reference JEDEC MS-012 variation AA.



#### **IMPORTANT NOTICE**

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